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CLASS

ORIGINAL

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Application/Control	No.
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10576721

Examiner

HENG CHAN

SUBCLASS

Applicant(s)/Patent Under Reexamination

NON-CLAIMED

SEINO ET AL.

INTERNATIONAL CLASSIFICATION

Art Unit

1728

CLAIMED

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☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47																					
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/HENG CHAN/ Examiner.Art Unit 1728	09/14/2011	Total Claims Allowed:				
(Assistant Examiner)	(Date)	1	4			
/JENNIFER MICHENER/ Supervisory Patent Examiner.Art Unit 1728	09/16/2011	O.G. Print Claim(s)	O.G. Print Figure			
(Primary Examiner)	(Date)	1	N/A			

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